

Quarterly Reliability Monitoring Results

Quarters: Q1/2020 to Q4/2020

Based on structural similarity

Supplier		User Part Number				
Nexperia B.V.		PMEG3030EP-Q				
Name of Laboratory		Part Description				
Assembly reliability labs		Nexperia DHAM Schottky SMD package				
AEC-Q101 Test		Test Conditions	Duration	# Lots	# Quantity	# Rejects
# 1	TEST Pre- and Post-Stress Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below
# 2	PC Preconditioning	JESD22-A113 Bake Tamb = 125 °C Soak Tamb = 85 °C, RH = 85% Reflow soldering	24 hours 168 hours 3 cycles	675	48500	0
# 5	HTRB High Temperature Reverse Bias	MIL-STD-750-1 M1038 Method A Tj = Tjmax, Vr = 100% of max. datasheet reverse voltage ^[1]	1000 hours	97	7760	0
# 7	TC Temperature Cycling	JESD22-A104 -65 °C to Tjmax, not to exceed 150°C	1000 cycles	142	11360	0
# 8	AC Autoclave	JESD22-A102 Tamb = 121 °C, RH = 100 % Pressure = 205 kPa (29.7 psia)	96 hours	142	11360	0
# 9	H3TRB High Humidity High Temperature Reverse Bias	JESD22-A101 Tamb = 85 °C, RH = 85%, VR > 80 % of rated reverse voltage ^[1]	1000 hours	140	11200	0
# 10	IOL Intermittent Operating Life	MIL-STD-750 Method 1037 ton = toff, devices powered to insure ΔTj = 100 °C for 15000 cycles	1000 hours	141	11280	0
# 20	RSH Resistance to Solder Heat	JESD22-A111 260 °C ± 5 °C	10 s	110	3300	0
# 21	SD Solderability	J-STD-002 Test method B and D		288	2880	0

[1] The physical limitations of Schottky diodes have to be considered (thermal runaway).

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, AEC-Q101 Test # 5)

Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia DHAM	Schottky	7760	0	0,55	1,83E+09

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